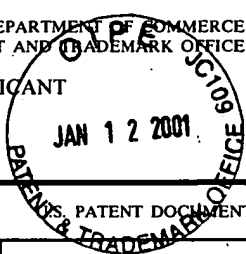


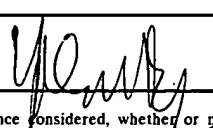
Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1518	SERIAL NO. 09/653,156
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Vishnu K. Agarwal	
				FILING DATE August 31, 2000	GROUP 2831



PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<div style="font-size: 2em;">+</div> <div style="font-size: 2em;">91</div>	AA	09/653,149	Derderian			08/31/00	
	AB	09/652,532	Derderian			08/31/00	
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						

FOREIGN PATENT DOCUMENTS							
Document Number	Date	Country	Class	Subclass	Translation		
					Yes	No	
AM							
AN							
AO							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
<div style="font-size: 2em;">+</div>	AP	A.W. Ott, et al., "Atomic layer controlled deposition of Al ₂ O ₃ films using binary reaction sequence chemistry" Applied Surface Science (107) 1996, pps. 128-136.	
	AQ		
	AR		

EXAMINER 	DATE CONSIDERED 11/17/07
--	--------------------------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PCT-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI22-1518SERIAL NO.
09/653,156LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)

APPLICANT Vishnu K. Agarwal

FILING DATE
August 31, 2000GROUP
2831

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>h</i>	AA	6,180,481	01-2001	Deboer et al			
<i>h</i>	AB	6,218,256	04-2001	Agarwal			
<i>h</i>	AC	6,104,049	08-2000	Solayappan et al			
<i>h</i>	AD	6,180,447	01-2001	Park et al			
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AM							
	AN							
	AO							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

	AP		
	AQ		
	AR		

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
M122-1518SERIAL NO.
09/653,156LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)

APPLICANT Vishnu K. Agarwal

FILING DATE
August 31, 2000GROUP
2831

U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
K	AA	6,274,428	08/2001	Wu			
	AB	6,124,158	09/2000	Dautartas et al			
	AC	6,144,060	11/2000	Park et al			
	AD	5,316,982	05/1994	Taniguchi			
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AM							
	AN							
	AO							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

	AP			
	AQ			
	AR			

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.